

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner Nathan W. Ha	Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0084536 A1	07-2002	Sundahl et al.	257/784
*	B	US-2005/0110136 A1	05-2005	Rakshani, Vafa James	257/724
*	C	US-6,246,118 B1	06-2001	Buynoski, Matthew S.	257/758
*	D	US-5,365,103 A	11-1994	Brown et al.	257/497
*	E	US-5,128,737 A	07-1992	van der Have, Leonard A.	257/503
*	F	US-2006/0131748 A1	06-2006	Seshan, Krishna	257/737
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.